



IN THE UNITED STATES  
PATENT AND TRADEMARK OFFICE

PATENT APPLICATION

\*\*\*\*\*

**INVENTORS:**

Yinon Degani  
Charlie Chunlei Gao  
King Lien Tai

**CASE:** S1

**FIRST CLASS MAIL**

These papers are being deposited  
as FIRST CLASS MAIL with the  
US POST OFFICE addressed to:  
COMMISSIONER FOR PATENTS  
ARLINGTON, VA 22313-1450  
by *John W. Hinde*  
date July 13, 2004

\*\*\*\*\*

**SERIAL NO.:** 10/053,818

**GROUP ART UNIT:** 2829

**FILING DATE:** 01/22/02

**EXAMINER:** Nguyen, Vinh P

**TITLE:** TESTING INTEGRATED CIRCUITS

**COMMISSIONER FOR PATENTS**  
**ARLINGTON, VA 22313-1450**

In response to the final Office Action mailed 04/13/04 please amend the  
above- identified application as follows, and consider the remarks that follow the  
amendments.

Please change the title to read:

-- MEMBRANE TEST APPARATUS FOR INTEGRATED  
CIRCUIT TESTING --

Please amend the claims as follows: